

<b>Notice of References Cited</b>	Application/Control No. 10/600,738		Applicant(s)/Patent Under Reexamination SMITH ET AL.	
	Examiner Paula W. Klimach		Art Unit 2135	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,642,394	06-1997	Rothschild, Peter John	378/57
*	B	US-6,523,166	02-2003	Mishra et al.	717/174
*	C	US-2003/0126464	07-2003	McDaniel et al.	713/201
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Lian, <sup>me</sup> <del>Tien</del> Delay Modeling and Sample Time Selection For Networked Control Systems, 2001, Proceedings of ASME-DSC, Vol.XX, pages 1-8
	V	Hogg, A Photometricity and Extinction Monitor At The Apache Point Observatory, 2001 The Astronomical Journal, pages 2129-2138.
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.